Abstracts

On-wafer characterization of millimeter-wave antennas for wireless applications

R.N. Simons and R.Q. Lee. "On-wafer characterization of millimeter-wave antennas for wireless applications." 1999 Transactions on Microwave Theory and Techniques 47.1 (Jan. 1999 [T-MTT]): 92-96.

This paper demonstrates a deembedding technique and a direct on-substrate measurement technique for fast and inexpensive characterization of miniature antennas for wireless applications at millimeter-wave frequencies. The technique is demonstrated by measurements on a tapered slot antenna (TSA). The measured results at Ka-band frequencies include input impedance, mutual coupling between two TSA's, and absolute gain of TSA.

❑ Return to main document.